Refine Search

Your wildcard search against 10000 terms has yielded the results below.

Your result set for the last L# is incomplete.

The probable cause is use of unlimited truncation. Revise your search strategy to use limited truncation.

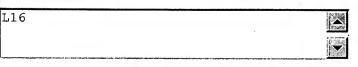
Seai	CII	Results	-

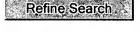
Terms	Documents	
L9 same mask\$ same select\$	10	

Database:

US Pre-Grant Publication Full-Text Database
US Patents Full-Text Database
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EPO Abstracts Database
JPO Abstracts Database
Derwent World Patents Index
IBM Technical Disclosure Bulletins

Search:











Search History

DATE: Sunday, June 10, 2007 Purge Queries Printable Copy Create Case

Set Name	Query	Hit Count	Set Name
side by side			result set
DB = USPT,	USOC,EPAB,JPAB,DWPI,TDBD; PLUR=	YES; OP = OR	
<u>L16</u>	19 same mask\$ same select\$	10	<u>L16</u>
<u>L15</u>	L11 same equation	1	<u>L15</u>
<u>L14</u>	L13 and equation	C	<u>L14</u>
<u>L13</u>	L12 and l11	3	<u>L13</u>
<u>L12</u>	mask\$ adj1 circuit\$	4433	<u>L12</u>
<u>L11</u>	L9 same compress\$	117	<u>L11</u>
<u>L10</u>	L9 same compress\$	117	<u>L10</u>
<u>L9</u>	test adj1 response	2880	<u>L9</u>
<u>L8</u>	L7 same 11	10	<u>L8</u>
<u>L7</u>	L6 same compress\$	874	<u>L7</u>
<u>L6</u>	decompress\$ adj1 circuit\$	1204	<u>L6</u>
<u>L5</u>	L4 same test\$	9	<u>L5</u>
<u>L4</u>	L1 same compress\$	149	<u>L4</u>
<u>L3</u>	L2 same compress\$	1	<u>L3</u>

L1 same equation mask\$ adj1 data

55 <u>L2</u> 5864 <u>L1</u>

END OF SEARCH HISTORY

First Hit

Previous Doc

Next Doc Go to Doc#

Cenerate Collection Print

L5: Entry 6 of 9

File: EPAB

Apr 7, 2005

DOCUMENT-IDENTIFIER: WO 2005031378 A1

TITLE: METHOD AND SYSTEM FOR SELECTIVELY MASKING TEST RESPONSES

Abstract Text (1):

CHG DATE=20050419 STATUS=0>An apparatus for testing an integrated circuit (10) that comprises a compactor (22) to compress test responses from a circuit-under-test (14) that is part of an integrated circuit (10), and masking circuitry (18) coupled between the circuit-under-rest and the compactor (22) for masking one or more of the test responses from the circuit-under-test (14). The masking circuitry (18) further comprises decompression circuitry for receiving compressed mask data and providing decompressed mask data.

Previous Doc

Next Doc

Go to Doc#

First Hit Fwd Refs

Previous Doc Next Doc Go to Doc# **Cenerate Collection**

L8: Entry 1 of 10

File: USPT

Aug 22, 2006

DOCUMENT-IDENTIFIER: US 7095808 B1

** See image for Certificate of Correction ** TITLE: Code puncturing method and apparatus

CLAIMS:

27. A method of using puncture masks comprising: retrieving a compressed puncture mask from a semiconductor memory, the compressed puncture mask being generated via a compression circuitry that compresses puncture mask data; decompressing the compressed puncture mask via a decompression circuitry to generate the puncture mask data, wherein the compressing of the puncture mask comprises: generating a first set of bits based on the puncture mask; generating a second set of bits by performing an XOR function with the first set of bits and the puncture mask; and compressing the second set or bits; and deleting particular bits from a data sequence according to the puncture mask data in the decompressed puncture mask.

34. An integrated circuit having a memory wherein the memory comprises a plurality of compressed puncture masks, each comprised puncture mask being generated via a compression circuitry that compresses puncture mask data, wherein the compressing of the puncture mask includes generating a first set of bits based on the puncture mask, generating a second set of bits by performing an XOR function with the first set of bits and the puncture mask data, and compressing the second set of bits, the compressed puncture mask being retrieved from the memory and decompressed via a decompression circuitry to generate the puncture mask data, the puncture mask data in the decompressed puncture mask being used to delete particular bits from a data sequence.

> Previous Doc Next Doc Go to Doc#